

Application Serial No. 10/773,524
Response to Office Action

Customer No. 01933

Attorney Docket No. 04083/LH

This paper is being submitted
via EFS-Web on November 17, 2008

**IN THE UNITED STATES PATENT
AND TRADEMARK OFFICE**

Applicant(s): Takashi YONEYAMA, et al.

Serial No. : 10/773,524

Confirm. No.: 7190

Filed : February 6, 2004

For : DEFECT INSPECTION APPARATUS AND
DEFECT INSPECTION METHOD

Art Unit : 2624

Examiner : Tsung Yin Tsai

In the event that this Paper is late filed, and the necessary petition for extension of time is not filed concurrently herewith, please consider this as a Petition for the requisite extension of time, and to the extent not already paid, authorization to charge the extension fee to Account No. 06-1378. In addition, authorization is hereby given to charge any fees for which payment has not been submitted, or to credit any overpayments, to Account No. 06-1378.

R E S P O N S E

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

S I R :

This is responsive to the Office Action mailed May 20, 2008, the term for response to which is extended by three months by Petition filed concurrently herewith to November 20, 2008.

Remarks begin on page 2 of this paper.